Application/Control No.	Applicant(s)/Patent under Reexamination
10/722,178	MASON, JAMES STEPHEN
Examiner	Art Unit
Hai L. Nguyen	2816

	SEAR	CHED	
Class	Subclass	Date	Examiner
331	16,17	4/18/2005	HLN
327	311,312		
327	551-559	V	V
Update	Search	9/30/2005	HLN
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
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